4 Introduction to Photovoltaics Failure Analysis and Reliability
Benjamin B. Yang
Photovoltaics (PV) are becoming an increasingly important solution to the demand for renewable energy. Read about common failure mechanisms in the PV industry and the significant overlap with FA techniques and methods in microelectronics.

12 A Through-Silicon Metrology Target for Solid Immersion Lenses, Part I: Metrology Chip and Example
William Lo and Howard Marks
End-users and tool vendors must have a reliable, objective means of determining solid immersion lens performance. Part I of this article describes the resolution criteria for a metrology target that evaluates high-numerical-aperture lenses for backside imaging.

21 ESREF 2014 in Berlin
Christian Boit
This review includes highlights from the 25th anniversary of ESREF, which focused on organic devices in 2014.

24 ISTFA 2014 Wrap-Up
A recap of the ISTFA 2014 event includes General Chair Dan Bodoh’s wrap-up, a summary of the Panel Discussion, highlights from the four User’s Groups, as well as a list of the ISTFA Best and Outstanding Papers and Posters.

ABOUT THE COVER
Broadcom system on a chip still mounted on the package with the silicon substrate completely removed. Photo by Gadi Matushansky, TechInsights, First Place Winner in Color Images, 2014 EDFAS Photo Contest.

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